# DABiC-IV, 20-BIT SERIAL-INPUT, LATCHED SOURCE DRIVER

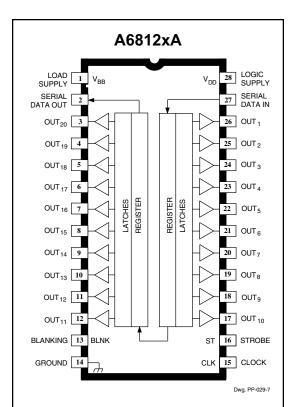
The A6812– devices combine a 20-bit CMOS shift register, accompanying data latches and control circuitry with bipolar sourcing outputs and pnp active pull downs. Designed primarily to drive vacuum-fluorescent displays, the 60 V and -40 mA output ratings also allow these devices to be used in many other peripheral power driver applications. The A6812- features an increased data input rate (compared with the older UCN/UCO5812-F) and a controlled output slew rate.

The CMOS shift register and latches allow direct interfacing with microprocessor-based systems. With a 3.3 V or 5 V logic supply, they will operate to at least 10 MHz.

A CMOS serial data output permits cascade connections in applications requiring additional drive lines. Similar devices are available as the A6809– and A6810– (10 bits), A6811– (12 bits), and A6818– (32 bits).

The A6812– output source drivers are npn Darlingtons, capable of sourcing up to 40 mA. The controlled output slew rate reduces electromagnetic noise, which is an important consideration in systems that include telecommunications and/or microprocessors and to meet government emissions regulations. For inter-digit blanking, all output drivers can be disabled and all sink drivers turned on with a BLANK-ING input high. The pnp active pull-downs will sink at least 2.5 mA.

Two temperature ranges are available for optimum performance in commercial (suffix S-) or industrial (suffix E-) applications. Package styles are provided for through-hole DIP (suffix -A), surface-mount SOIC (suffix -LW), or minimum-area surface-mount PLCC (suffix -EP). Copper lead frames, low logic-power dissipation, and low output-saturation voltages allow these drivers to source 25 mA from all outputs continuously to more than +43°C (suffix -LW), +61°C (suffix -EP), or  $+77^{\circ}$ C (suffix -A).



### **ABSOLUTE MAXIMUM RATINGS** at $T_A = 25^{\circ}C$

Logic Supply Vollage, V <sub>DD</sub>
Driver Supply Voltage, V <sub>BB</sub> <b>60 V</b>
Continuous Output Current Range,
I <sub>OUT</sub> 40 mA to +15 mA
land the Maltaga Danaga

Input Voltage Range,

 $V_{IN}$  ..... -0.3 V to  $V_{DD}$  + 0.3 V Package Power Dissipation,

P<sub>D</sub>...... See Graph Operating Temperature Range, TA

(Suffix 'E-') ..... -40°C to +85°C (Suffix 'S-') ..... -20°C to +85°C

Storage Temperature Range,

T<sub>S</sub> ..... -55°C to +125°C

Caution: These CMOS devices have input static protection (Class 2) but are still susceptible to damage if exposed to extremely high static electrical charges.

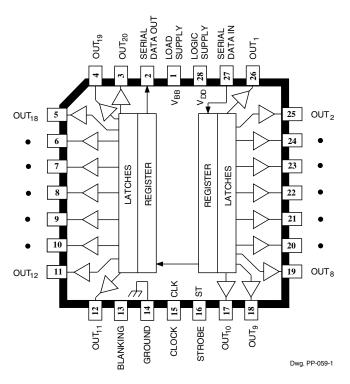
#### **FEATURES**

- High-Speed Data Storage
- 60 V Minimum Output Breakdown
- High Data Input Rate
- PNP Active Pull-Downs
- Controlled Output Slew Rate Low Output-Saturation Voltages
  - Low-Power CMOS Logic and Latches
  - Improved Replacements for TL5812-, UCN5812-, and UCQ5812-

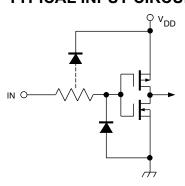
Complete part number includes a suffix to identify operating temperature range (E- or S-) and package type (-A, -EP, or -LW). Always order by complete part number, e.g., **A6812SLW**.



#### A6812xEP

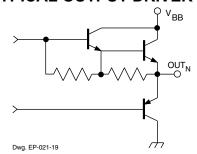


### **TYPICAL INPUT CIRCUIT**

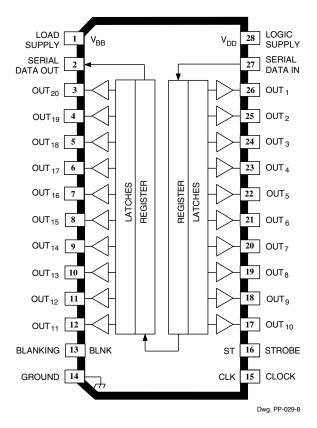


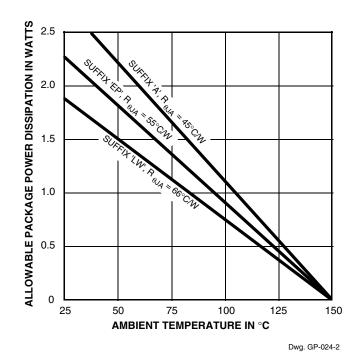
Dwg. EP-010-5

#### TYPICAL OUTPUT DRIVER

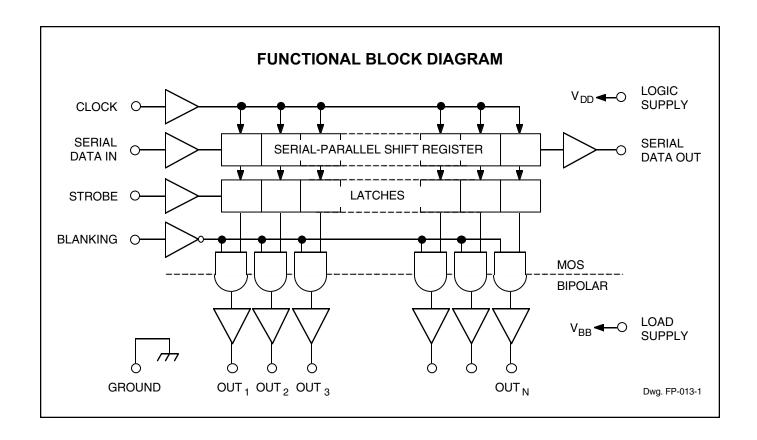


### A6812xLW









### **TRUTH TABLE**

Serial			Shift Register Contents					Serial		Latch Contents						Output Contents						
Data Input	Clock Input		l <sub>2</sub>	l <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>	Data Output			l <sub>2</sub>	I <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>	Blanking	I <sub>1</sub>	l <sub>2</sub>	l <sub>3</sub>		I <sub>N-1</sub>	I <sub>N</sub>
Н	۲	Н	R <sub>1</sub>	R <sub>2</sub>		R <sub>N-2</sub>	R <sub>N-1</sub>	R <sub>N-1</sub>														
L	7	L	R <sub>1</sub>	R <sub>2</sub>		R <sub>N-2</sub>	R <sub>N-1</sub>	R <sub>N-1</sub>														
Х	7	R <sub>1</sub>	R <sub>2</sub>	$R_3$		R <sub>N-1</sub>	$R_N$	R <sub>N</sub>														
		Х	Χ	Χ		Χ	Χ	Х	L	R <sub>1</sub>	$R_2$	$R_3$		R <sub>N-1</sub>	$R_{N}$							
		P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	P <sub>N</sub>	P <sub>N</sub>	Н	P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	P <sub>N</sub>	L	P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>		P <sub>N-1</sub>	$P_{N}$
										Χ	Χ	Χ		Χ	Χ	Н	L	L	L		L	L

 $L = Low \ Logic \ Level$   $H = High \ Logic \ Level$  X = Irrelevant  $P = Present \ State$   $R = Previous \ State$ 

# ELECTRICAL CHARACTERISTICS at $T_A$ = +25°C (A6812S-) or over operating temperature range (A6812E-), $V_{BB}$ = 60 V unless otherwise noted.

			Limits	@ V <sub>DD</sub>	= 3.3 V	Limits			
Characteristic	Symbol	Test Conditions	MIn.	Тур.	Max.	Min.	Тур.	Max.	Units
Output Leakage Current	I <sub>CEX</sub>	V <sub>OUT</sub> = 0 V	_	<-0.1	-15	_	<-0.1	-15	μΑ
Output Voltage	V <sub>OUT(1)</sub>	I <sub>OUT</sub> = -25 mA	57.5	58.3	_	57.5	58.3	_	V
	V <sub>OUT(0)</sub>	I <sub>OUT</sub> = 1 mA	_	1.0	1.5	_	1.0	1.5	V
Output Pull-Down Current	I <sub>OUT(0)</sub>	V <sub>OUT</sub> = 5 V to V <sub>BB</sub>	2.5	5.0	_	2.5	5.0	_	mA
Input Voltage	V <sub>IN(1)</sub>		2.2	_	_	3.3	_	_	V
	V <sub>IN(0)</sub>		_	_	1.1	_	_	1.7	V
Input Current	I <sub>IN(1)</sub>	$V_{IN} = V_{DD}$	_	<0.01	1.0	_	<0.01	1.0	μΑ
	I <sub>IN(0)</sub>	V <sub>IN</sub> = 0 V	_	<-0.01	-1.0	_	<-0.01	-1.0	μΑ
Input Clamp Voltage	V <sub>IK</sub>	I <sub>IN</sub> = -200 μA	_	-0.8	-1.5	_	-0.8	-1.5	V
Serial Data Output Voltage	V <sub>OUT(1)</sub>	I <sub>OUT</sub> = -200 μA	2.8	3.05	_	4.5	4.75	_	V
	V <sub>OUT(0)</sub>	I <sub>OUT</sub> = 200 μA	_	0.15	0.3	_	0.15	0.3	٧
Maximum Clock Frequency	f <sub>c</sub>		10*	_	_	10*	_	_	MHz
Logic Supply Current	I <sub>DD(1)</sub>	All Outputs High	_	0.25	0.75	_	0.3	1.0	mA
	I <sub>DD(0)</sub>	All Outputs Low	_	0.25	0.75	_	0.3	1.0	mA
Load Supply Current	I <sub>BB(1)</sub>	All Outputs High, No Load	_	3.0	6.0	_	3.0	6.0	mA
	I <sub>BB(0)</sub>	All Outputs Low	_	0.2	20	_	0.2	20	μΑ
Blanking-to-Output Delay	t <sub>dis(BQ)</sub>	C <sub>L</sub> = 30 pF, 50% to 50%	_	0.7	2.0	_	0.7	2.0	μs
	t <sub>en(BQ)</sub>	C <sub>L</sub> = 30 pF, 50% to 50%	_	1.8	3.0	_	1.8	3.0	μs
Strobe-to-Output Delay	t <sub>p(STH-QL)</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	_	0.7	2.0	_	0.7	2.0	μs
	t <sub>p(STH-QH)</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	_	1.8	3.0	_	1.8	3.0	μs
Output Fall Time	t <sub>f</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	2.4	_	12	2.4	_	12	μs
Output Rise Time	t <sub>r</sub>	$R_L = 2.3 \text{ k}\Omega, C_L \leq 30 \text{ pF}$	2.4	_	12	2.4	_	12	μs
Output Slew Rate	dV/dt	$R_L = 2.3 \text{ k}\Omega, C_L \le 30 \text{ pF}$	4.0	_	20	4.0	_	20	V/μs
Clock-to-Serial Data Out Delay	t <sub>p(CH-SQX)</sub>	I <sub>OUT</sub> = ±200 μA	_	50	_	_	50		ns

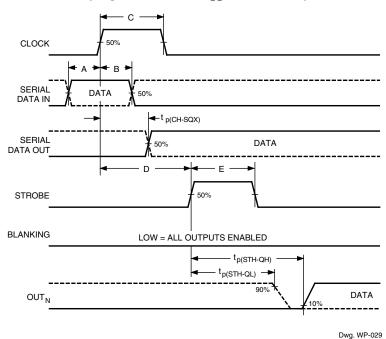
Negative current is defined as coming out of (sourcing) the specified device terminal.

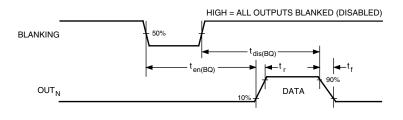
Typical data is is for design information only and is at  $T_A = +25^{\circ}C$ .

<sup>\*</sup> Operation at a clock frequency greater than the specified minimum is possible but not warranteed.



# TIMING REQUIREMENTS and SPECIFICATIONS (Logic Levels are V<sub>DD</sub> and Ground)





speeds may be attainable with increased supply voltage; operation at high temperatures will reduce the specified maximum clock frequency.

Serial Data present at the input is transferred to the shift register on the logic "0" to logic "1" transition of the CLOCK input pulse. On succeeding CLOCK pulses, the registers shift data information towards the SERIAL DATA OUTPUT. The SERIAL DATA must appear at the input prior to the rising edge of the CLOCK input waveform.

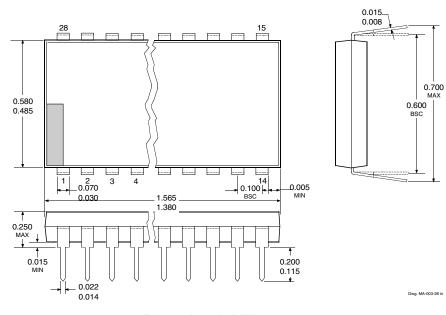
Dwg. WP-030

Information present at any register is transferred to the respective latch when the STROBE is high (serial-to-parallel conversion). The latches will continue to accept new data as long as the STROBE is held high. Applications where the latches are bypassed (STROBE tied high) will require that the BLANKING input be high during serial data entry.

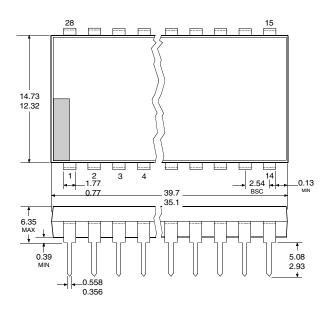
When the BLANKING input is high, the output source drivers are disabled (OFF); the pnp active pull-down sink drivers are ON. The information stored in the latches is not affected by the BLANKING input. With the BLANKING input low, the outputs are controlled by the state of their respective latches.

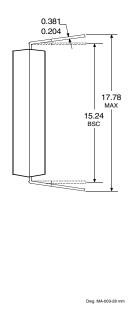
#### A6812EA & A6812SA

Dimensions in Inches (controlling dimensions)



# Dimensions in Millimeters (for reference only)





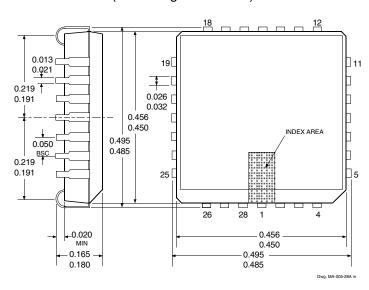
NOTES: 1. Exact body and lead configuration at vendor's option within limits shown.

- 2. Lead spacing tolerance is non-cumulative.
- 3. Lead thickness is measured at seating plane or below.
- 4. Supplied in standard sticks/tubes of 12 devices.

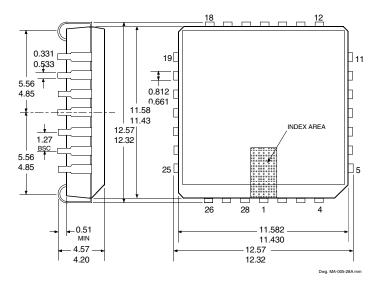


#### A6812EEP & A6812SEP

(add "TR" to part number for tape and reel)
Dimensions in Inches
(controlling dimensions)



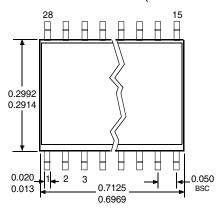
# Dimensions in Millimeters (for reference only))

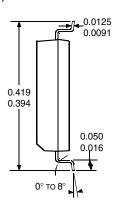


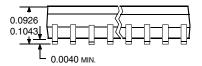
- NOTES: 1. Exact body and lead configuration at vendor's option within limits shown.
  - 2. Lead spacing tolerance is non-cumulative.
  - 3. Supplied in standard sticks/tubes of 38 devices or add "TR" to part number for tape and reel.

#### A6812ELW & A6812SLW

(add "TR" to part number for tape and reel)
Dimensions in Inches
(for reference only)

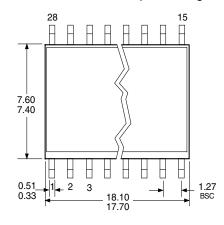


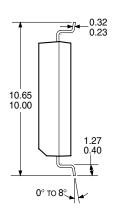


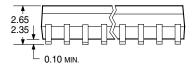


Dwg. MA-008-28A in

# Dimensions in Millimeters (controlling dimensions)







Dwg. MA-008-28A mm

- NOTES: 1. Exact body and lead configuration at vendor's option within limits shown.
  - 2. Lead spacing tolerance is non-cumulative.
  - 3. Supplied in standard sticks/tubes of 27 devices or add "TR" to part number for tape and reel.



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# POWER INTERFACE DRIVERS

Function	Output I	Ratings*	Part Number <sup>†</sup>							
SERIAL-INPUT LATCHED DRIVERS										
8-Bit (saturated drivers)	-120 mA	50 V‡	5895							
8-Bit	350 mA	50 V	5821							
8-Bit	350 mA	80 V	5822							
8-Bit	350 mA	50 V‡	5841							
8-Bit	350 mA	80 V‡	5842							
8-Bit (constant-current LED driver)	75 mA	17 V	6275							
8-Bit (DMOS drivers)	250 mA	50 V	6595							
8-Bit (DMOS drivers)	350 mA	50 V‡	6A595							
8-Bit (DMOS drivers)	100 mA	50 V	6B595							
10-Bit (active pull-downs)	-25 mA	60 V	5810-F and 6809/10							
12-Bit (active pull-downs)	-25 mA	60 V	5811 and 6811							
16-Bit (constant-current LED driver)	75 mA	17 V	6276							
20-Bit (active pull-downs)	-25 mA	60 V	5812-F and 6812							
32-Bit (active pull-downs)	-25 mA	60 V	5818-F and 6818							
32-Bit	100 mA	30 V	5833							
32-Bit (saturated drivers)	100 mA	40 V	5832							
PARALLEI	-INPUT LATCHED	DRIVERS								
4-Bit	350 mA	50 V‡	5800							
8-Bit	-25 mA	60 V	5815							
8-Bit	350 mA	50 V‡	5801							
8-Bit (DMOS drivers)	100 mA	50 V	6B273							
8-Bit (DMOS drivers)	250 mA	50 V	6273							
SPECIAL-PURPOSE DEVICES										
Unipolar Stepper Motor Translator/Driver	1.25 A	50 V‡	5804							
Addressable 8-Bit Decoder/DMOS Driver	250 mA	50 V	6259							
Addressable 8-Bit Decoder/DMOS Driver	350 mA	50 V‡	6A259							
Addressable 8-Bit Decoder/DMOS Driver	100 mA	50 V	6B259							
Addressable 28-Line Decoder/Driver	450 mA	30 V	6817							

<sup>\*</sup> Current is maximum specified test condition, voltage is maximum rating. See specification for sustaining voltage limits. Negative current is defined as coming out of (sourcing) the output.



<sup>†</sup> Complete part number includes additional characters to indicate operating temperature range and package style.

<sup>‡</sup> Internal transient-suppression diodes included for inductive-load protection.